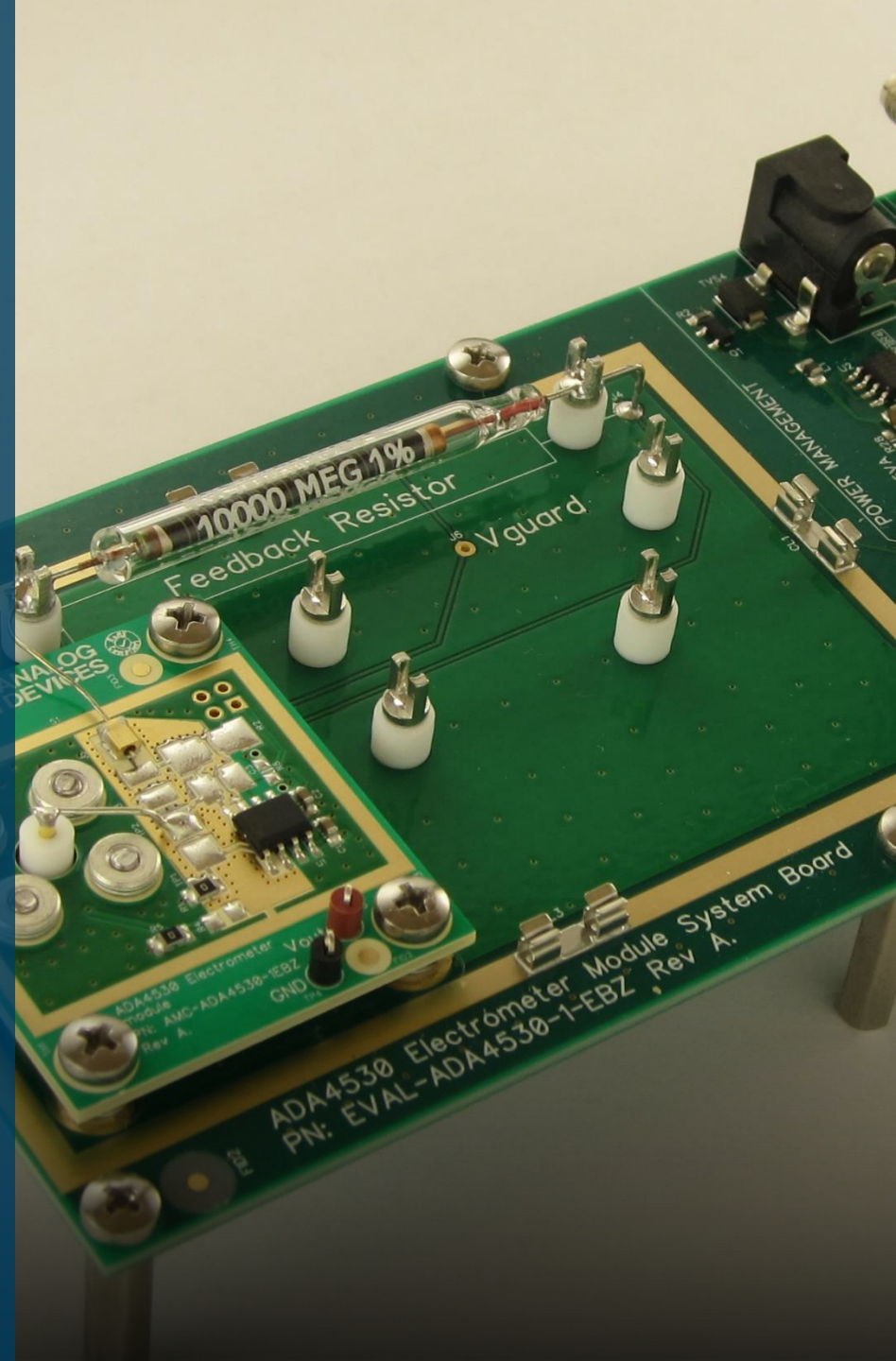


# Femtoammeter Design: Development Module for Charged Particle Detection

GUSTAVO CASTRO

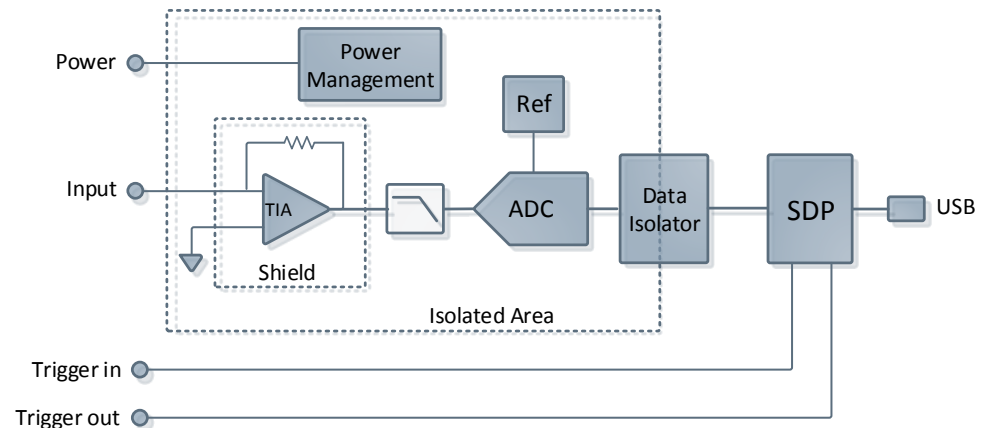
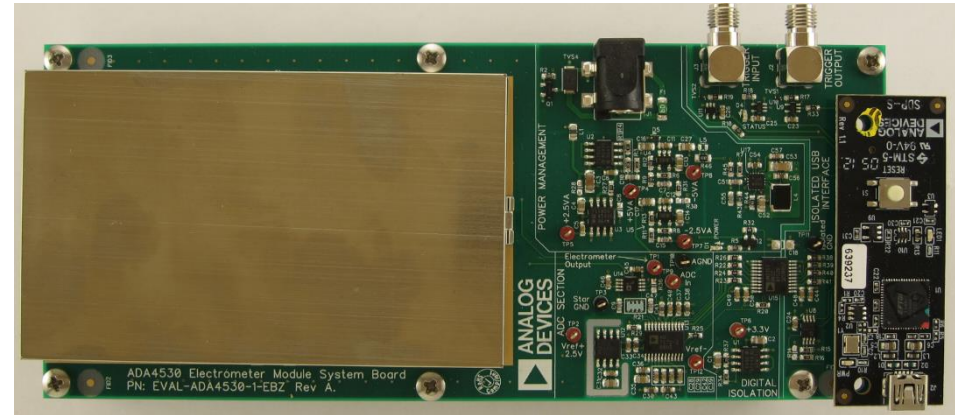
SYSTEM APPLICATIONS ENGINEER

PRECISION INSTRUMENTATION

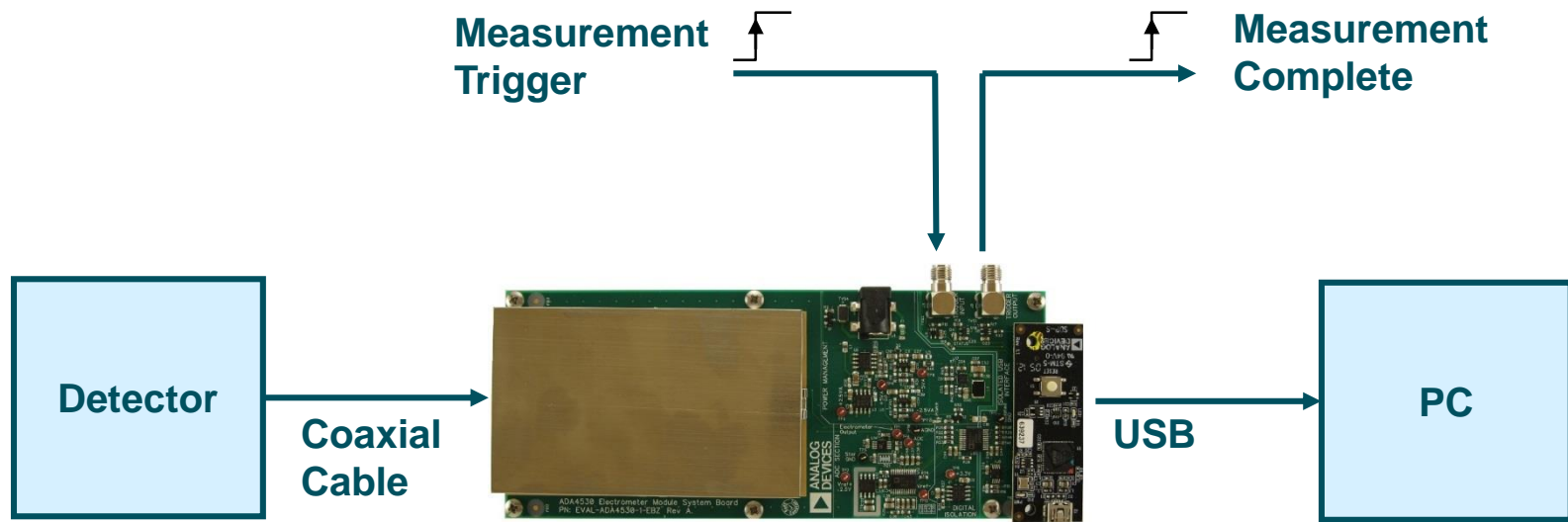


# Femtoammeter Module

- ▶ Development module for sensors with low-level current output
  - Direct interface to photodiodes, faraday cups through SMA connector
- ▶ Features
  - **<10fA sensitivity** with  $10\text{G}\Omega$  transimpedance
    - 400pA measurement range
    - Shielding
    - Isolation with **ADuM3151**
  - Femtoampere input bias op amp
    - **ADA4530-1**
  - 24-bit resolution ADC
    - **AD7172-2**
  - USB interface to PC via SDP
    - **ADP7118, ADP2442, ADP7182**
  - Measurement synchronization
    - Trigger in/out signals
  - Can be reconfigured as electrometer front-end



# Example Application



Photodiode  
Faraday cup  
Photomultiplier tubes (PMT)  
Electron-multiplier

...

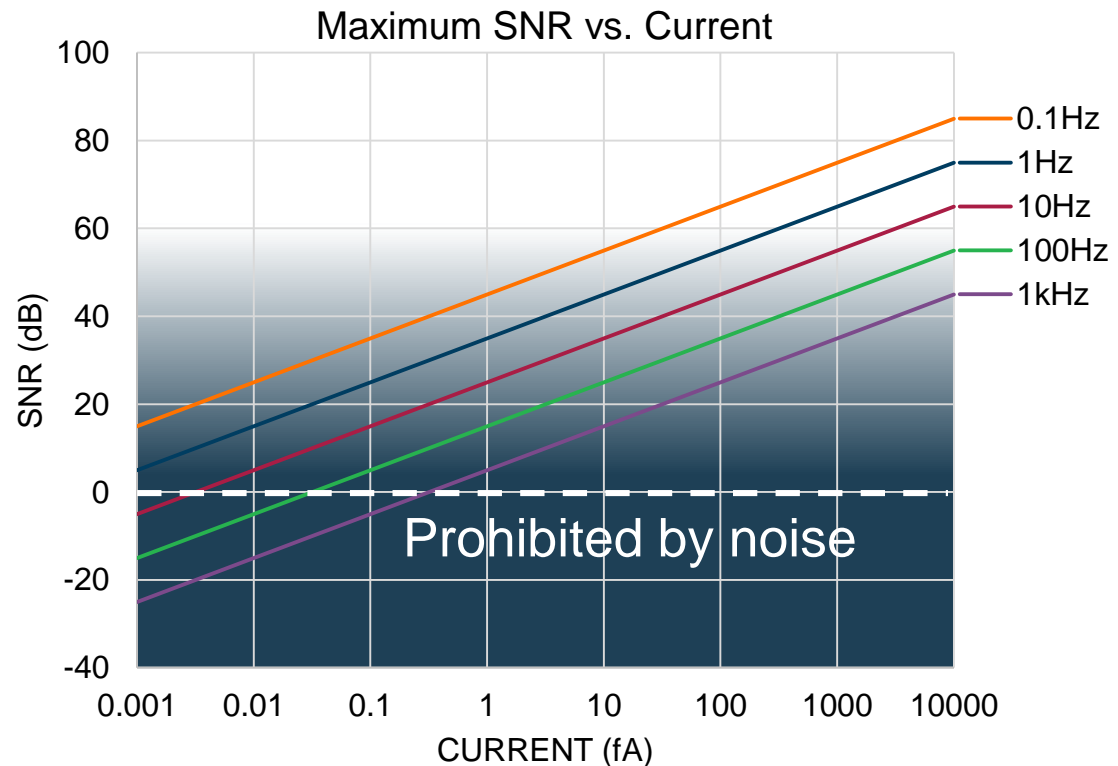
# Fundamental Measurement Limits

- ▶ The discrete nature of electrical current generates “shot noise”
- ▶ Shot noise increases as the square root of current

$$i_i = \sqrt{2qI\Delta f}$$

- ▶ At very low-level currents, shot noise can be greater than the measurement
  - Lower bandwidth; longer measurement times are required

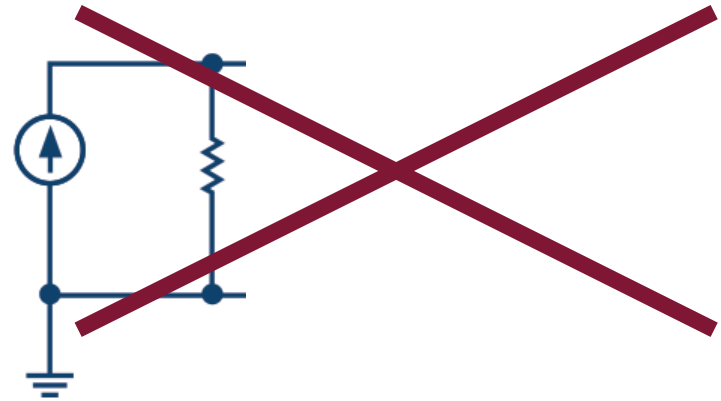
$$SNR = \sqrt{\frac{I}{2q\Delta f}}$$



# Measuring Low-Level Currents

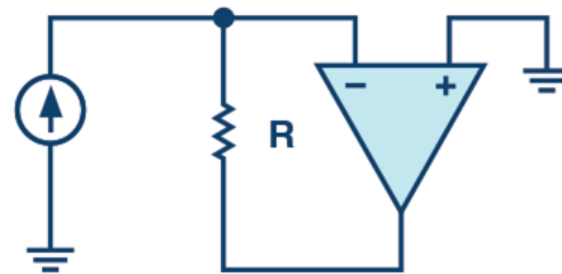
## ► Option 1: resistor + buffer/amplifier

- The current can flow through a resistor and then amplify
- Increases burden voltage
- Increases noise



## ► Option 2: transimpedance amplifier

- The current still flows through a resistor
- The op amp is used to reduce burden voltage
- Keeps amplifier noise and error contribution low



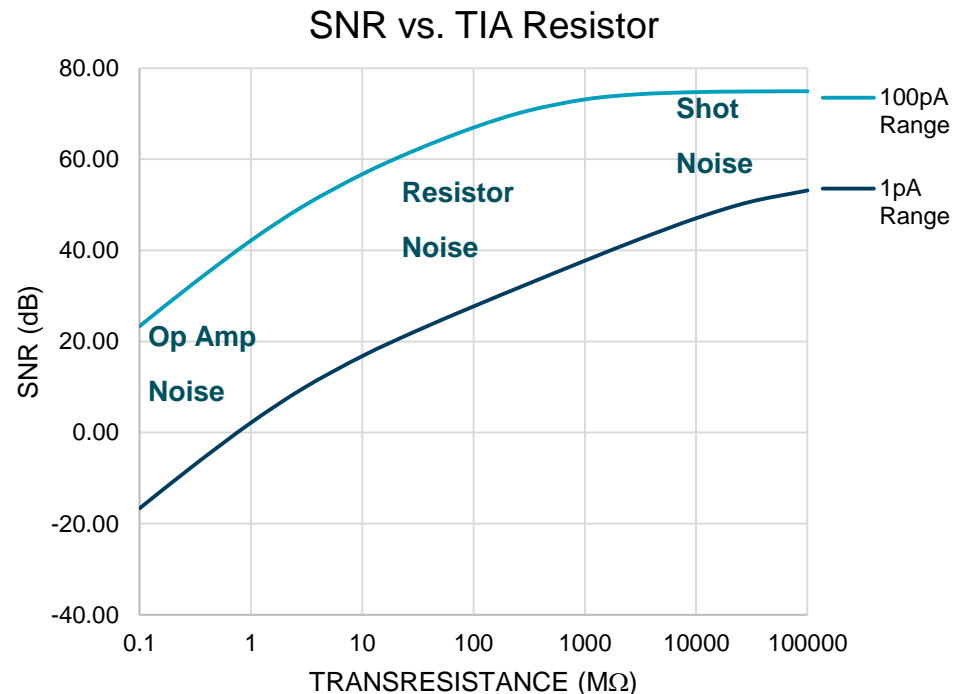
# Resistor and Op Amp Noise

- ▶ Resistor
- ▶ The greater the resistor, the better SNR
  - Signal increases proportional to resistor value (Ohm's law)
  - Noise increases per square-root of resistor value (Johnson noise)

$$i_r = \sqrt{\frac{4kT}{R} \Delta f}$$

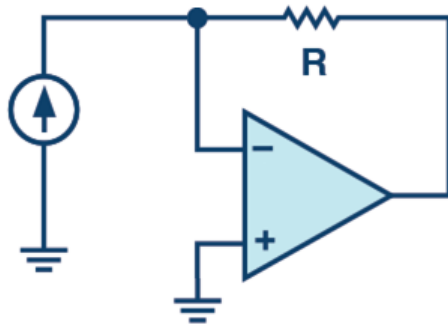
- ▶ Op Amp
- ▶ At low bandwidth, TIA has unity noise gain
  - The op amp's voltage noise contribution to current noise gets divided by resistor value

$$i_a = e_a / R$$

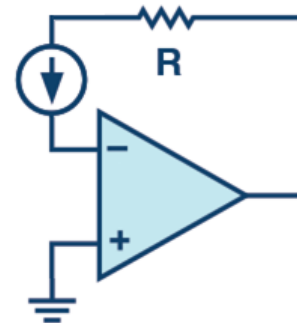


# Resistor and Op Amp Noise

- ▶ In conclusion, to measure small currents, use
  - A large resistor
  - A very low noise op amp
  - A very low input-bias op amp like the **ADA4530-1**

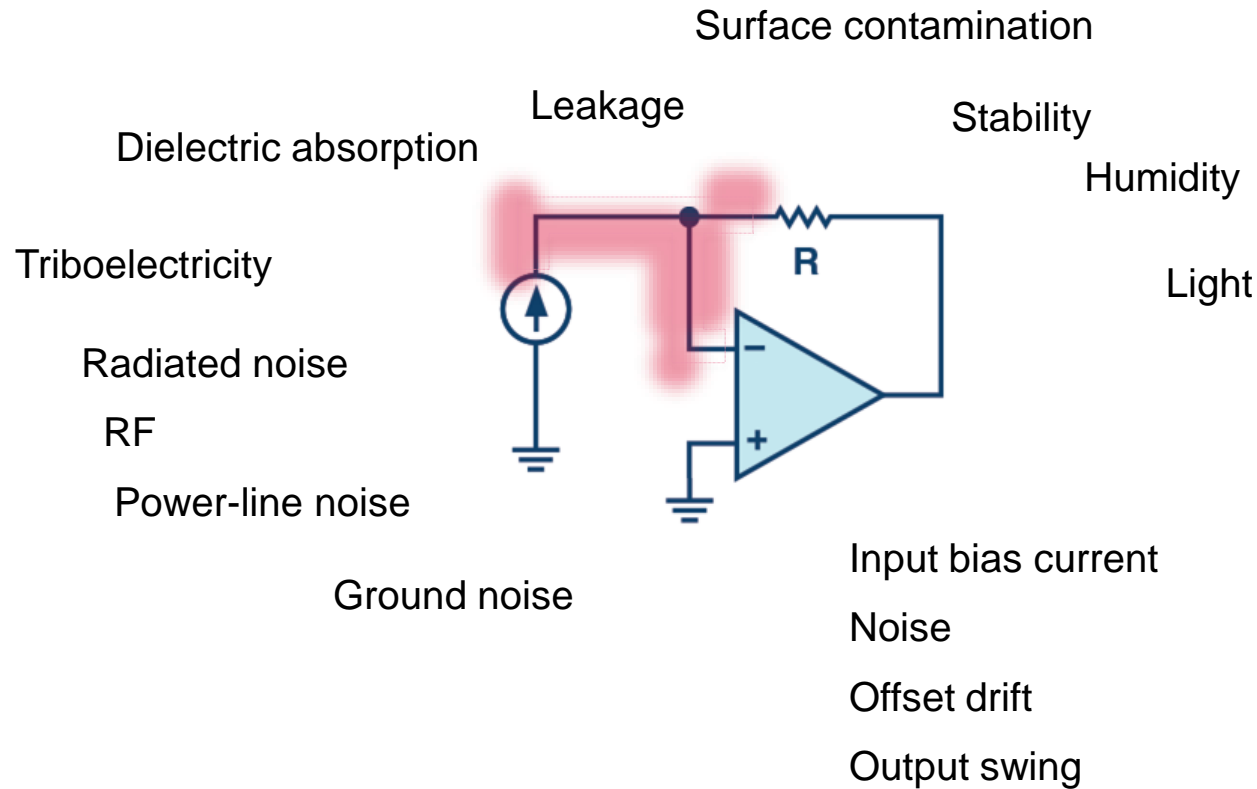


- ▶ With large resistors
  - The amplifier will become slower (due to frequency compensation)
  - The op amp's input bias current can saturate the output
  - Doubles every 10°C



- ▶ Example:  $100\text{pA} \cdot 10\text{G}\Omega = 1\text{V}$

# The Implementation Problems

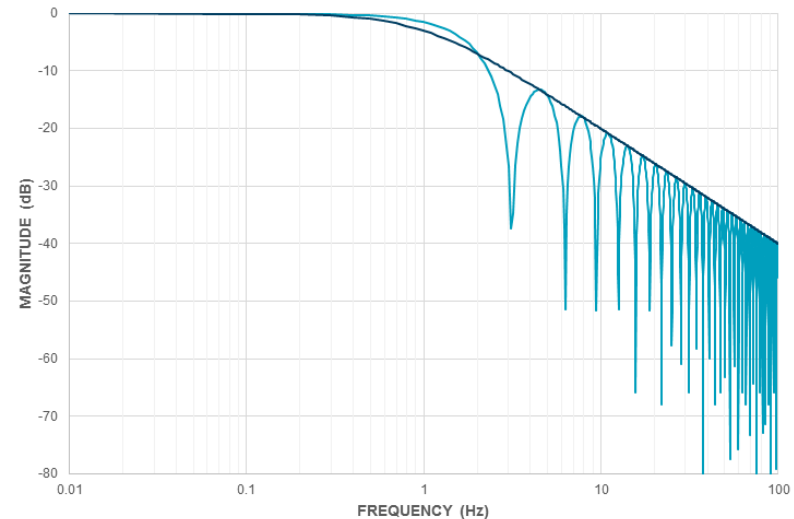




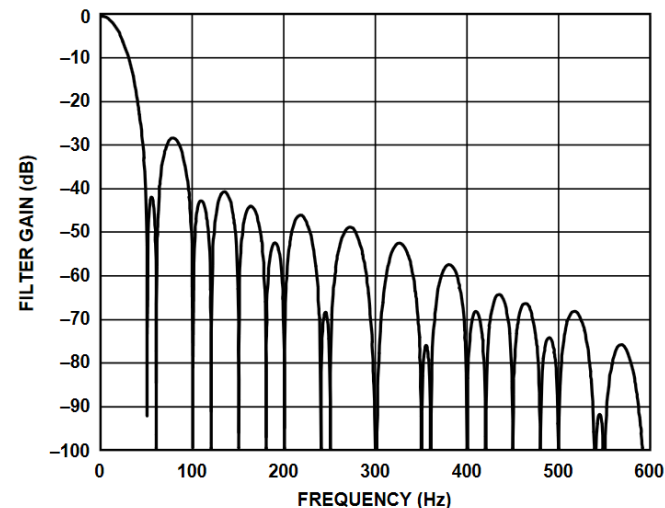
# Noise Reduction: The Effect of Averaging vs. Filtering

- ▶ Sensitivity requires minimizing the noise
- ▶ Averaging and filtering reduce measurement bandwidth but work a little different
- ▶ The average of N samples:
  - Reduces the noise by  $\sqrt{N}$  (flat-band noise)
  - Reduces the effective maximum frequency by  $2^N$
  - Increases measurement time
  - Rejects frequencies at the notches
    - Good for power-line noise rejection
  - Produces aliasing above the notches
- ▶ Effectively a simple FIR filter
  - Can be arbitrarily short/long
  - Very popular these days
- ▶ Sigma-delta ADCs like AD7172 perform this function internally using specialized filters

1<sup>st</sup> Order Filter vs. Average

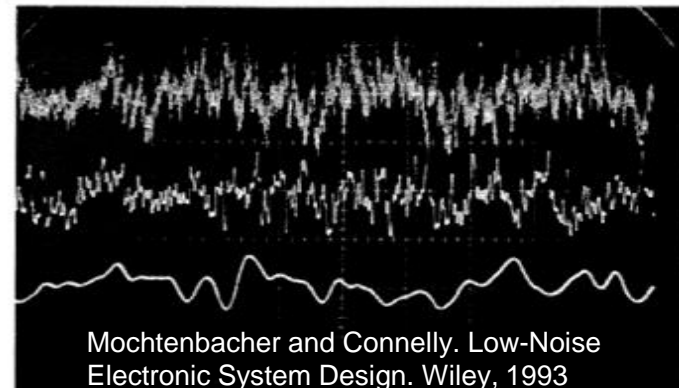
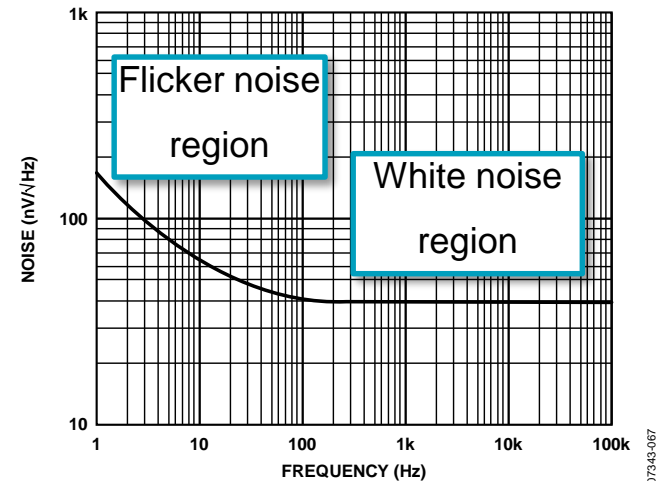


Example Filter Transfer Function in **AD7172-2**



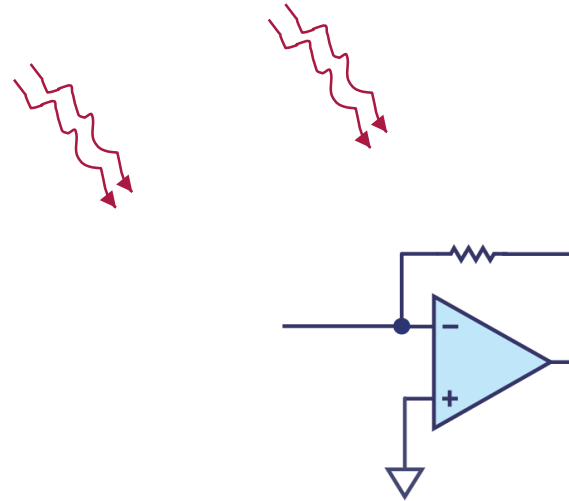
# Flicker Noise and Low-Level Measurements

- ▶ Flicker ( $1/f$ ) noise often limits measurement front-end sensitivity
- ▶ Noise reduction by filtering or averaging fails upon reaching the  $1/f$  corner
  - Averaging reduces flat-band noise
  - Noise amplitude is not reduced by  $\sqrt{N}$  after reaching this region
  - The longer the average, the longer we look at the signal, the lower we move on the frequency band
- ▶ Common flicker noise sources:
  - ICs and semiconductor devices
    - Op amps, references, diodes...
  - Resistor excess noise
    - Noise index sometimes available from manufacturers



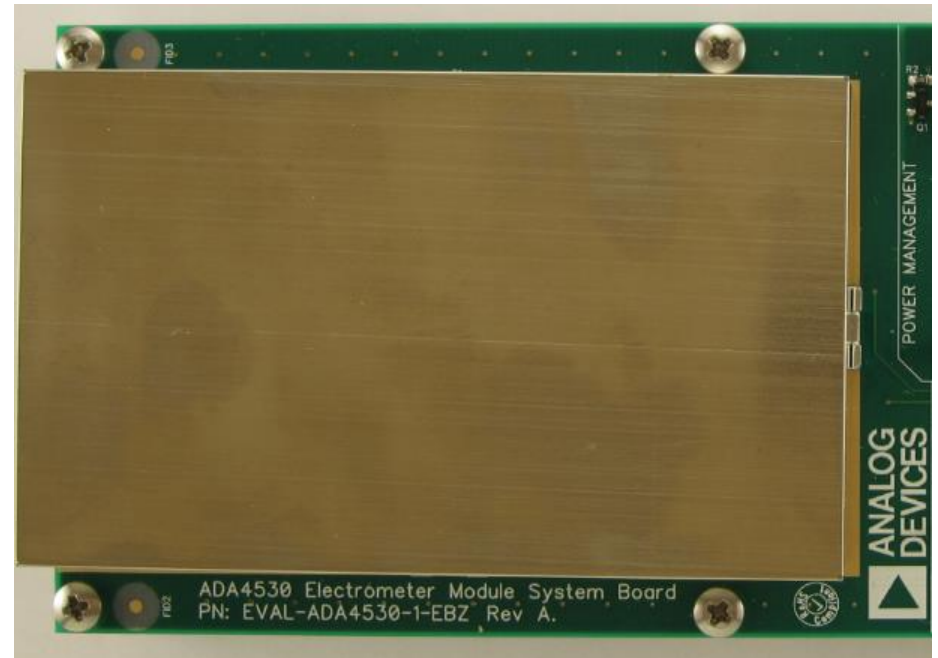
# Extrinsic Noise

- ▶ Main sources:
  - Power lines (50/60Hz)
  - RF (e.g. wireless communications)
- ▶ Reaches the circuit via
  - Emission
  - Conduction
- ▶ Reduced by
  - Shielding
  - Minimize inductive loops (e.g. twist wires)
  - Proper layout and grounding
  - Isolation
  - Power supply decoupling
  - Filtering



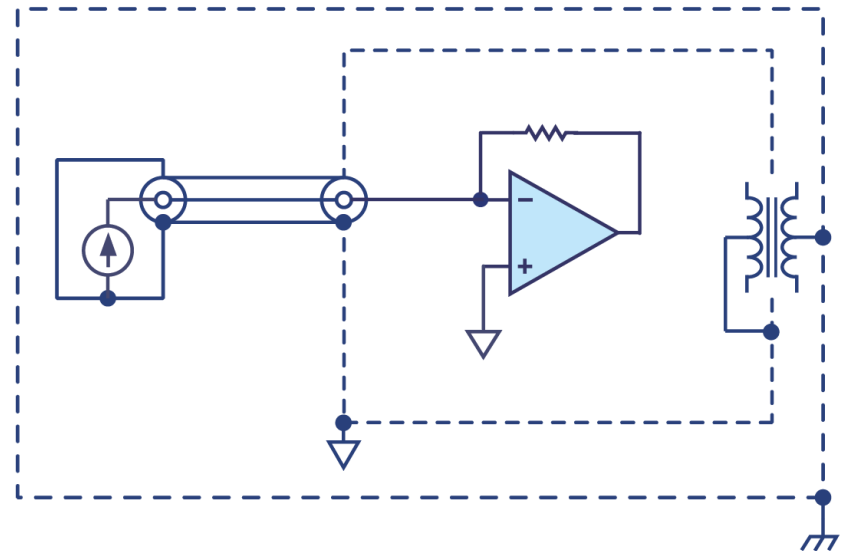
# Shielding

- ▶ Shields help keep stray fields away from sensitive nodes
- ▶ Shields should be grounded when exposed to operators for safety



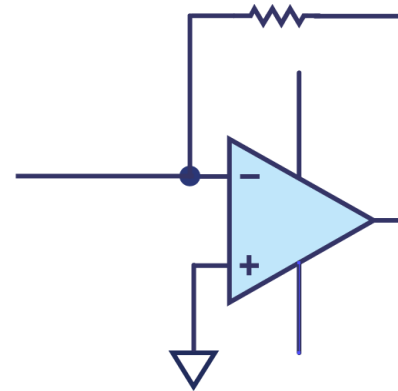
# Isolation

- ▶ Great for breaking ground loops, reduce noise
- ▶ But must bring data (**ADuM3151**) and power across isolation barrier
- ▶ Proper connections are required to avoid coupling of the common-mode current into the measurement
  - Or use batteries
- ▶ Shields can couple noise into isolated circuits
  - Keep shields away from sensitive nodes
  - Or use a driven shield (guard) inside the shield



# Surface and Board Leakage

- ▶ The surface of dielectrics has better conduction properties due to contamination, humidity, etc
  - This includes FR-4 and PTFE board materials, no matter how good their bulk properties are
- ▶ Sources of contamination:
  - Solder flux residue from assembly process
    - No-clean solder residue is difficult to remove
  - Dust and other particulate accumulation
- ▶ Washing assemblies is recommended after assembly
- ▶ Moisture reduces insulation properties of PCB and cables
  - Bake after wash to eliminate moisture absorption
  - Choose appropriate materials and perform measurements in controlled environments

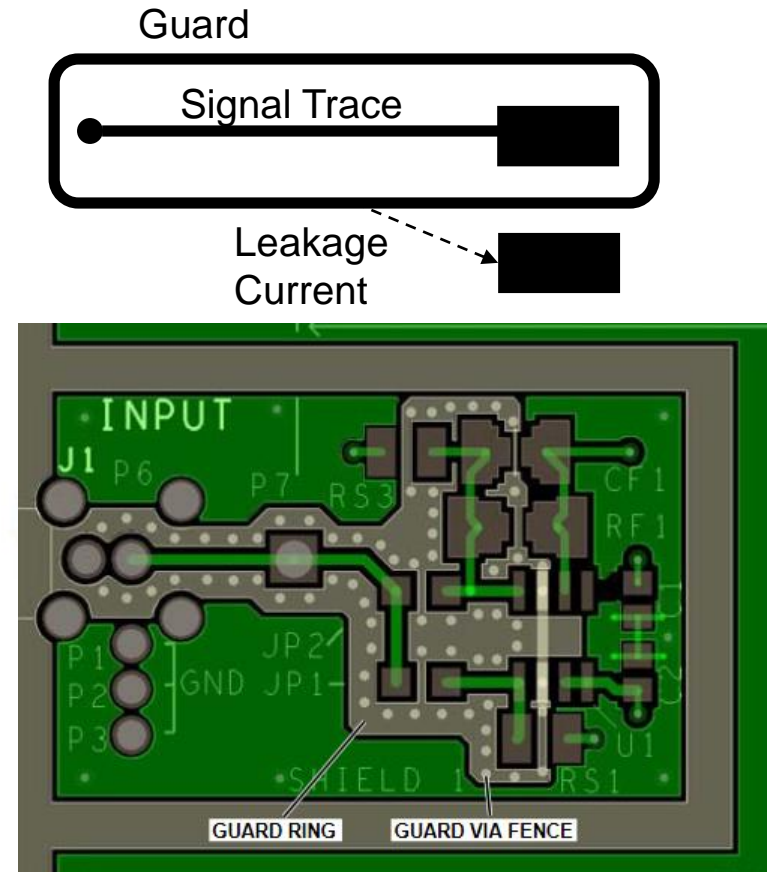


Material	Moisture Absorption (%)
Hi Pref FR-4	0.50
Nearly pure PTFE	0.02

*Source: Rogers Corp.*

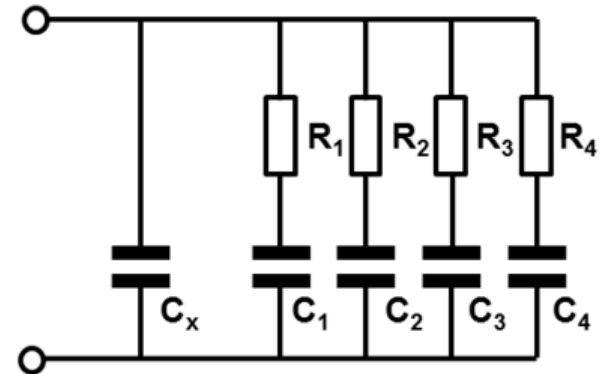
# Dealing with Leakage on the PCB

- ▶ Better layout yields better performance over time and environmental conditions
- ▶ Guard rings
  - Prevents sensitive current to flow through unwanted paths
  - Needs to be driven by an amplifier at the same potential as the input (e.g. a buffer)
- ▶ Remove solder mask
  - Eliminates the conduction path over the guard ring
  - Solder mask absorbs moisture too
- ▶ Board cuts



# Dielectric Absorption

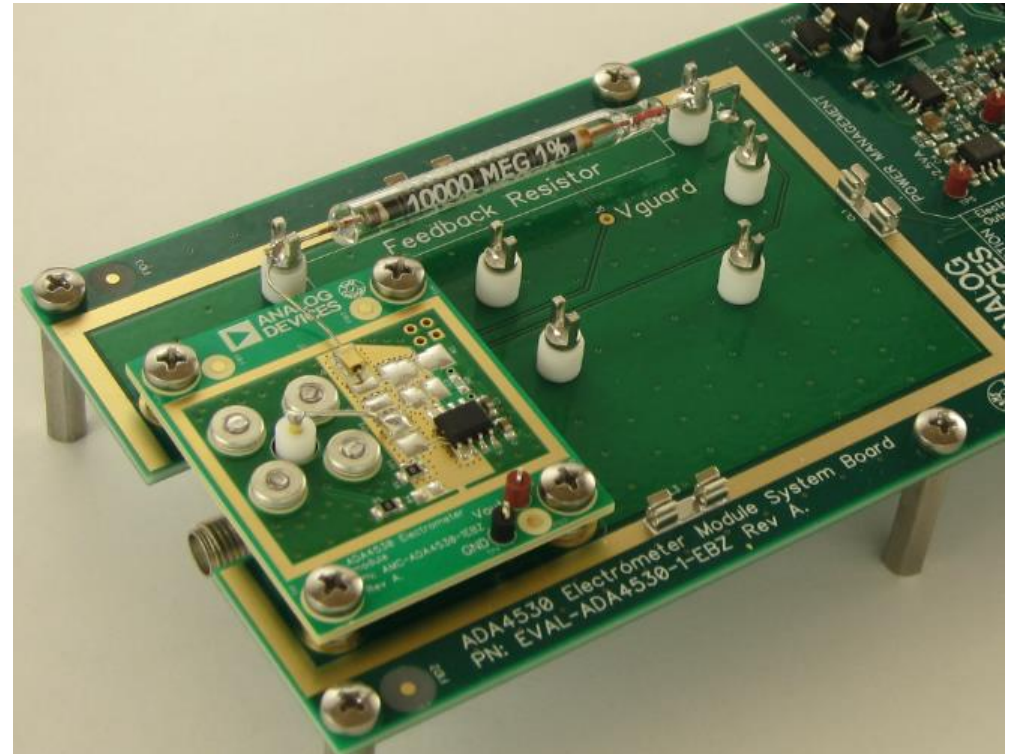
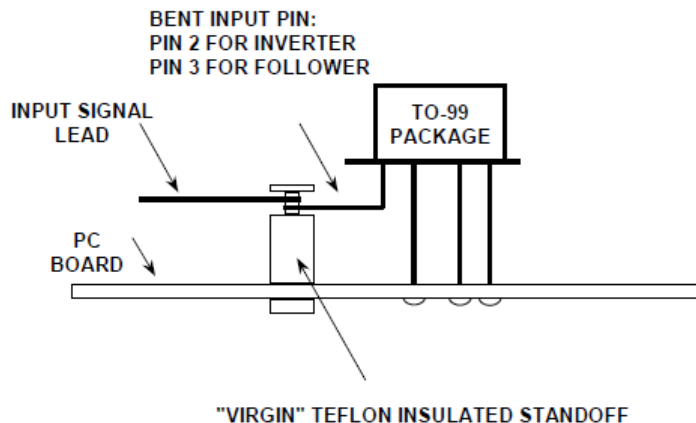
- ▶ Caused by the polarization of the dielectric between conductor plates upon application of an electric field
- ▶ Commonly observed in
  - Capacitors
  - Multilayer PCBs
- ▶ The polarization relaxation has a longer time constant than the capacitance formed by the plates
- ▶ Often modeled as an RC in parallel with the “ideal” capacitor
- ▶ This is also why large capacitors are handled with a bleeding resistor or a short (safety)





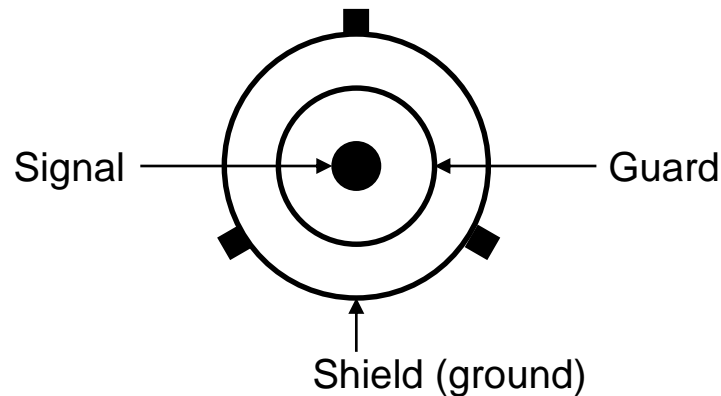
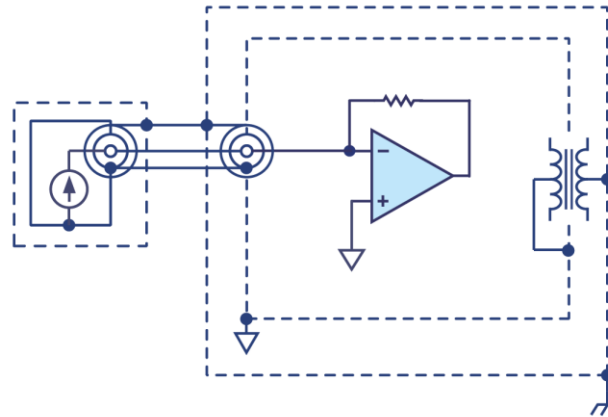
# Dealing with Dielectric Absorption in PCBs

- ▶ Use PTFE (Teflon™) laminates (Rogers Corp.)
- ▶ Stand-offs available for air-wiring
- ▶ Minimize absorbing material: board cuts



# Interconnects for Low-Current Measurement

- ▶ Cables and connectors
  - Shielding is a must
- ▶ BNC, SMA and coaxial cables are OK as long as there is very little potential difference between center conductor and shield
  - Cost effective
  - Some RF materials (PTFE) have also good low-leakage, low DA properties
  - Beware of safety with ground-isolated measurements
- ▶ Best: use triax connectors and cables
  - BNC to triax adapters available for interfacing to sensors



# Summary

- Design of low-level current measurement hardware requires attention to many details!

Problem	Cause	Solution
Leakage on PCB	Moisture and contamination	Guard rings, board cuts, dust covers
	Solder flux contamination	Avoid no-clean solder; wash and bake
Dielectric absorption	Charge trapped in dielectrics	Use PTFE in boards and cables, guarding
Cable leakage	Poor-quality insulation between conductors	Use PTFE-insulated cables or triax cables
Extrinsic noise	E/M fields, Powerline interference	Shielding and guarding
	Ground noise	Isolation
	Light-induced charge	Shielding/covers
	Mechanical vibrations, triboelectricity	Cable tie-downs

- A femtoammeter module solves many problems and enables quick and simple prototyping and evaluation

**QUESTIONS?**

**THANK YOU!**